

# **FDP5N50NZ / FDPF5N50NZ** N-Channel UniFET<sup>™</sup> II MOSFET 500 V, 4.5 A, 1.5 Ω

# Features

- R  $_{DS(on)}$  = 1.38  $\Omega$  (Typ.) @ V<sub>GS</sub> = 10 V, I<sub>D</sub> = 2.25 A
- Low Gate Charge (Typ. 9 nC)
- Low Crss (Typ. 4 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Imoroved Capability
- RoHS Compliant

## Applications

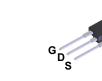
- LCD/LED TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply



FDP5N50NZ / FDPF5N50NZ N-Channel UniFET<sup>TM</sup> II MOSFET

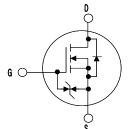
# Description

UniFET<sup>™</sup> II MOSFET is Fairchild Semiconductor<sup>®</sup>'s high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest onstate resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



TO-220

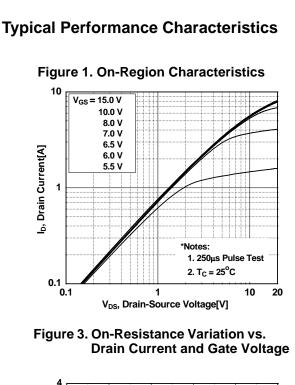


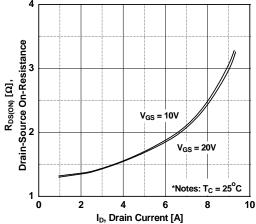


## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

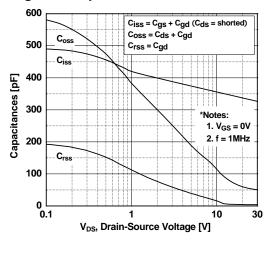
Symbol	Parameter			FDP5N50NZ	FDPF5N50NZ	Unit		
V <sub>DSS</sub>	Drain to Source Voltage			5	V			
V <sub>GSS</sub>	Gate to Source Voltage			E	V			
I <sub>D</sub>	Drain Current	-Continuous (T <sub>C</sub> = 25 <sup>o</sup> C)		4.5	4.5*	A		
		-Continuous (T <sub>C</sub> = 100 <sup>o</sup> C)		2.7	2.7*	A		
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	18	18*	Α		
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)			160		mJ		
I <sub>AR</sub>	Avalanche Current (Note 1)			4.5		Α		
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)			-	mJ			
dv/dt	Peak Diode Recovery dv/dt (Note 3)		10		V/ns			
P <sub>D</sub>	Power Dissipation	$(T_{\rm C} = 25^{\rm o}{\rm C})$		78	30	W		
		- Derate above 25°C		0.62	0.24	W/ºC		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150		°C		
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	°C			
	nited by maximum junction temperatu Characteristics	ıre						
Symbol	Parameter		FDP5N50NZ	FDPF5N50NZ	Unit			
R <sub>θJC</sub>	Thermal Resistance, Junction to Case, Max.			1.6	4.1			
R <sub>0CS</sub>	Thermal Resistance, Case to Sink Typ.			-	-	°C/W		
$R_{\theta JA}$	Thermal Resistance, Junctior	to Ambient, Max.		62.5	62.5			

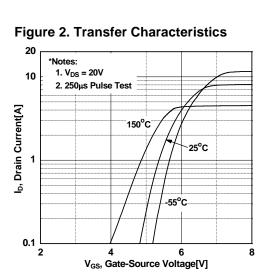
	Device	Package	e Reel Size	Таре	e Width		Quantit	y
FDP5N50NZ FDP5N50NZ T		TO-220			-	50		
FDPF5N50NZ FDPF5N50NZ TO-22		TO-220F	-		-		50	
l Char	acteristics T <sub>C</sub> =	= 25ºC unless c	otherwise noted					
	Parameter		Test Condition	ons	Min.	Тур.	Max.	Unit
teristic	S							
Drain to	Source Breakdown V	/oltage	$I_{D} = 250 \mu A, V_{GS} = 0V,$	T <sub>C</sub> = 25°C	500	-	-	V
	akdown Voltage Temperature		$I_D = 250\mu A$ , Referenced to $25^{\circ}C$		-	0.5	-	V/ºC
Zara Cr			$V_{DS} = 500V, V_{GS} = 0V$		-	-	1	
DSS Zero Gate Voltage Drain Currer		ent	$V_{DS} = 400V, V_{GS} = 0V, T_{C} = 125^{\circ}C$			-	10	μA
Gate to	to Body Leakage Current		$V_{GS} = \pm 25V, V_{DS} = 0V$		-	-	±10	μA
teristic	S							
Gate Th	nreshold Voltage		$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		3.0	-	5.0	V
		sistance			-	1.38	1.5	Ω
Forward			$V_{\rm DS} = 20V, I_{\rm D} = 2.25A$	-	3.54	-	S	
haracte	vistics							-1
						330	440	pF
	t Capacitance		$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz				-	pF
							-	pF
		6					-	nC
	-		V <sub>DS</sub> = 400V I <sub>D</sub> = 4.5A	s = 400V I <sub>D</sub> = 4.5A	-		-	nC
-	5		$V_{GS} = 10V$	_		_	nC	
				(Note 4,5)				
	•		V 250V L 454		-			ns
			$V_{DD} = 250V, I_{D} = 4.5A$ $V_{GS} = 10V, R_{GEN} = 25\Omega$ (Note 4,5)					ns
								ns
Turn-Of	Fall Time				-	21	50	ns
ce Dio	de Characteristic	s						
Maximu	mum Continuous Drain to Source Diode Forward Current				-	-	4.5	Α
	num Pulsed Drain to Source Diode Fo				-	-	18	Α
Drain to	Source Diode Forwar	d Voltage	$V_{GS} = 0V, I_{SD} = 4.5A$		-	-	1.4	V
Reverse	Recovery Time		$V_{GS} = 0V, I_{SD} = 4.5A$		-	210	-	ns
Reverse	Recovery Charge		dl <sub>F</sub> /dt = 100A/µs	(Note 4)	-	1.1	-	μC
	I Char Eteristic Drain to Breakdo Coeffici Zero Ga Gate to Eteristic Gate Th Static D Forward Characte Total Ga Gate to Gate to Charac Charac Charac Turn-Or Turn-Or Turn-Or Turn-Off Tu	I Characteristics T <sub>C</sub> = Parameter  Eteristics Drain to Source Breakdown V Breakdown Voltage Temperat Coefficient Zero Gate Voltage Drain Curre Gate to Body Leakage Currer  Eteristics Gate Threshold Voltage Static Drain to Source On Re Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitanc Total Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time rce Diode Characteristic Maximum Continuous Drain to Maximum Pulsed Drain to Source	I Characteristics T <sub>C</sub> = 25°C unless of Parameter  teristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current  teristics Gate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Total Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time rce Diode Characteristics Maximum Continuous Drain to Source Diode Forward Voltage Reverse Recovery Time	I Characteristics       Test Condition         Parameter       Test Condition         Iteristics       Indication         Drain to Source Breakdown Voltage       Indication         Breakdown Voltage Temperature Coefficient       Indication         Zero Gate Voltage Drain Current       Visc = 500V, Visc = 0V, Visc = 0V, Visc = 400V, Visc = 25V, Visc = 0V         Static Drain to Source On Resistance       Visc = 10V, Indication         Static Drain to Source On Resistance       Visc = 20V, Indication         Forward Transconductance       Visc = 25V, Visc = 0V         Characteristics       Input Capacitance       Visc = 25V, Visc = 0V         Input Capacitance       Visc = 25V, Visc = 0V       f = 1MHz         Characteristics       Visc = 10V       g = 400V Iii = 4.5A         Gate to Drain "Miller" Charge       Visc = 10V       G = 10V         Characteristics       Visc = 10V, Iii = 4.5A       Visc = 10V, Iii = 4.5A         Turn-On Delay Time       Visc = 10V, Rigen = 250       Visc = 10V, Rigen = 250         Turn-Off Fall Time       Visc = 00V, Iii = 4.5A       Visc = 00V, Iii = 4.5A         Maximum Continuous Drain to Source Diode Forward Current       Maximum Pulsed Drain to Source Diode Forward Current	I Characteristics $T_c = 25^{\circ}C$ unless otherwise noted         Parameter       Test Conditions         tteristics       Ip = 250 \muA, V_{GS} = 0V, T_c = 25^{\circ}C         Breakdown Voltage Temperature Coefficient       Ip = 250 \muA, Referenced to 25^{\circ}C         Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ Zero Gate Voltage Drain Current $V_{GS} = 400V, V_{GS} = 0V, T_c = 125^{\circ}C$ Gate to Body Leakage Current $V_{GS} = 10V, I_D = 250\mu$ A         Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 2.25A$ Forward Transconductance $V_{DS} = 20V, I_D = 2.25A$ (Note 4)         Characteristics       Input Capacitance $V_{DS} = 25V, V_{GS} = 0V$ (Note 4)         Characteristics       Volute Capacitance $V_{DS} = 400V I_D = 4.5A$ (Note 4.5)         Characteristics       V_{DD} = 250V, V_{GS} = 10V       (Note 4.5)       (Note 4.5)         Characteristics       V_{DD} = 250V, V_{GS} = 10V       (Note 4.5)         Characteristics       V_{DD} = 250V, I_D = 4.5A       (Note 4.5)         Characteristics       V_{DD} = 250V, I_D = 4.5A       (Note 4.5)         Characteristics       Maximum Continuous Drain to Source Diode Forward Current       (Note 4.5)         Characteristics       Maximum Continuous Drain to Source Diode Forwa	I Characteristics       T <sub>C</sub> = 25°C unless otherwise noted         Parameter       Test Conditions       Min.         Iteristics       Drain to Source Breakdown Voltage       I <sub>D</sub> = 250µA, V <sub>GS</sub> = 0V, T <sub>C</sub> = 25°C       500         Breakdown Voltage Temperature Coefficient       I <sub>D</sub> = 250µA, Referenced to 25°C       -         Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ -         Gate to Body Leakage Current $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ -         Gate to Body Leakage Current $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ -         Gate to Body Leakage Current $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ -         Gate Threshold Voltage $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ -         Gate Threshold Voltage $V_{GS} = 400V, V_{GS} = 0V, T_C = 125°C$ -         Forward Transconductance $V_{GS} = 10V, I_D = 2.50\muA$ 3.0         Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 2.25A$ -         Output Capacitance $V_{SS} = 25V, V_{GS} = 0V$ -         Input Capacitance $V_{CS} = 10V, I_D = 4.5A$ -         Gate to Source Gate Charge $V_{SS} = 10V, I_D = 4.5A$ -         Gate to Drain "Miller" Charge $V_{CS} = 10V, I_D = 4.5A$ -	$\begin{tabular}{ c c c c c } \hline I Characteristics $$T_{C} = 25^{\circ}C $$ unless otherwise noted $$ Min. Typ. there is the term of term $	$\begin{tabular}{ c c c c c c } \hline IC haracteristics & Min. Typ. Max. \\ \hline Parameter & Test Conditions & Min. Typ. Max. \\ \hline teristics & & & & & & & & & & & & & & & & & & &$

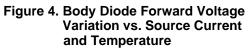


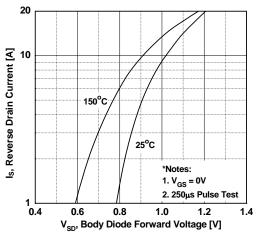




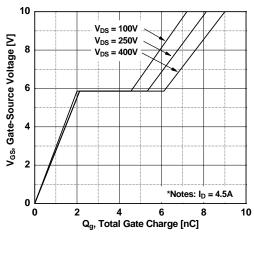




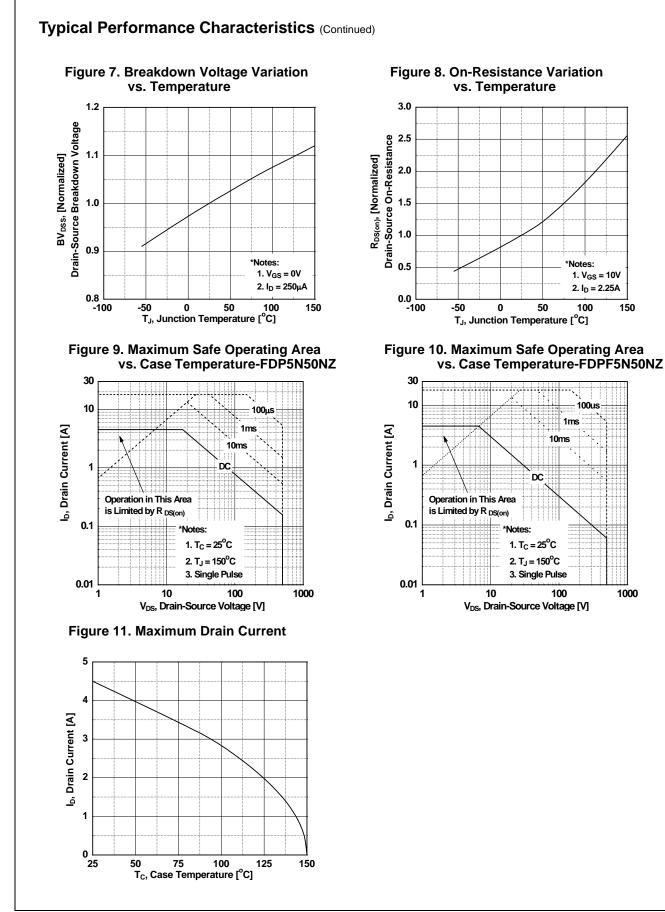






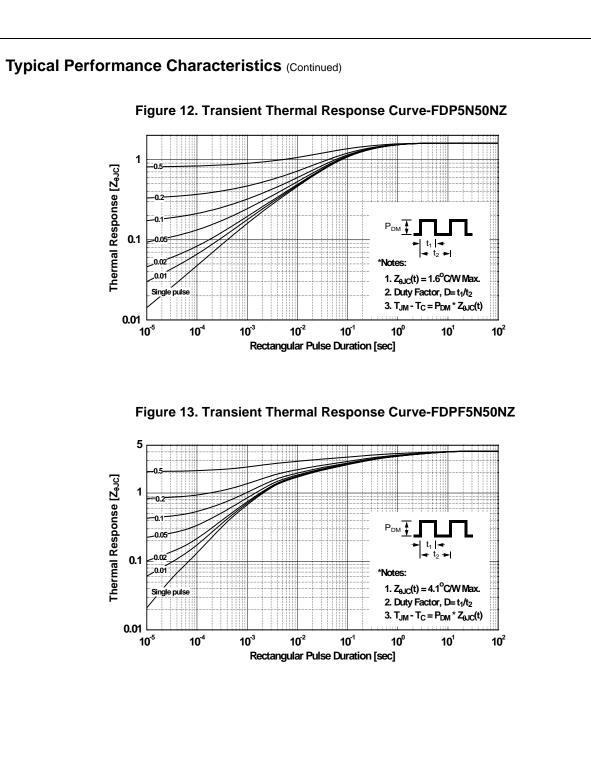


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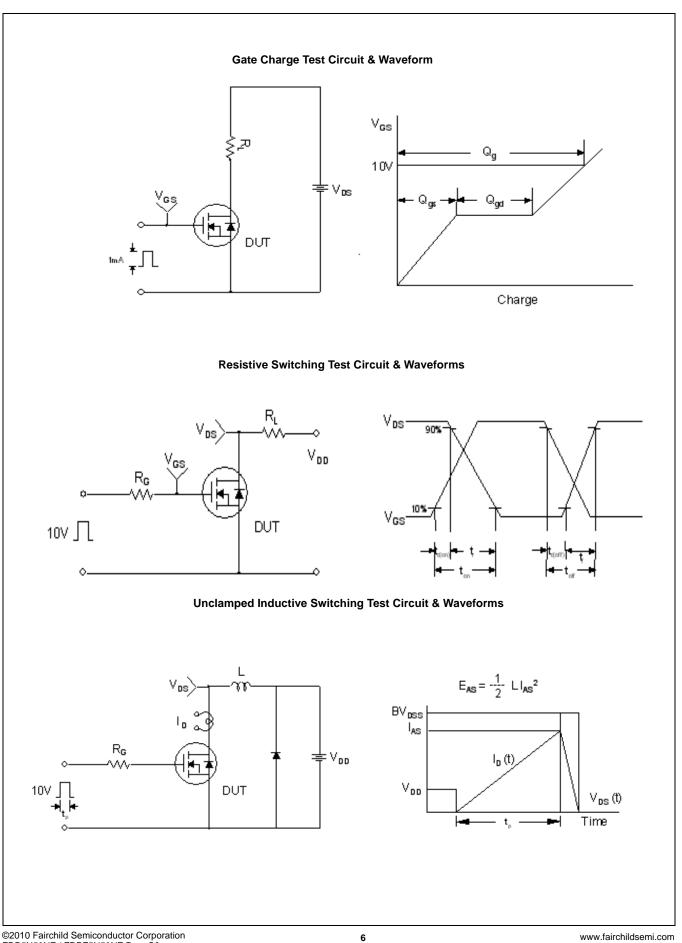
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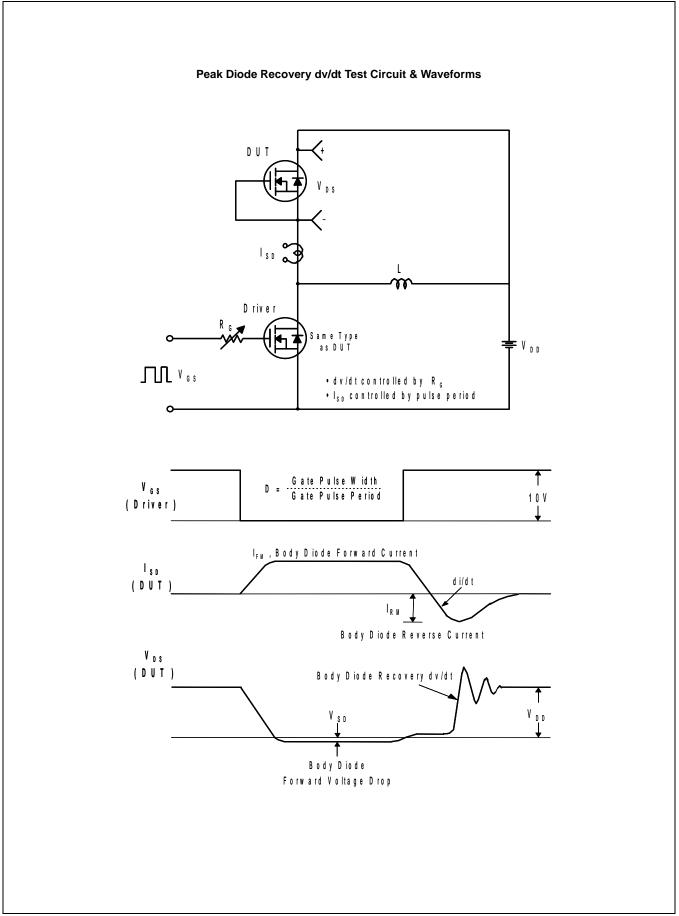
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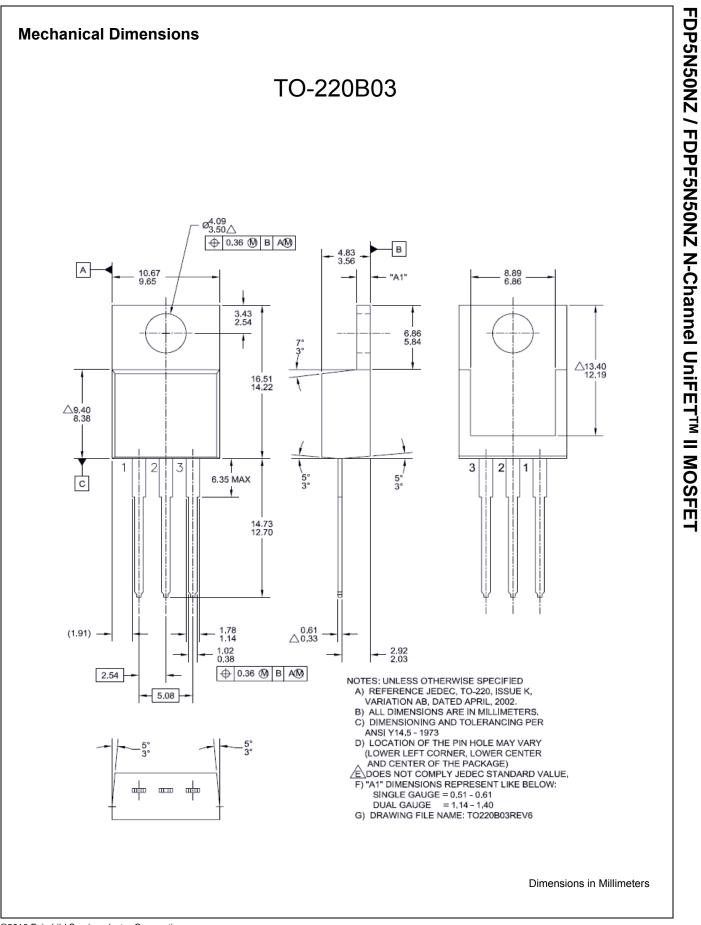


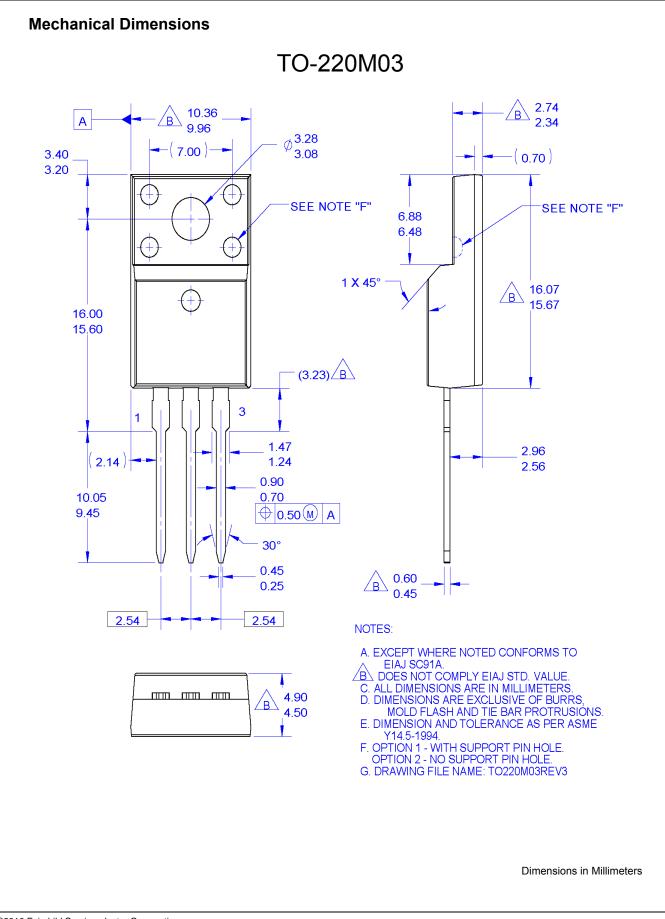
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